IPG No: P17263

CLAIMS

What is claimed is:

1 1. A method comprising

- 2 providing a wafer comprising a plurality of copper structures partially
- 3 encased in a hydrophobic interlayer dielectric layer, where top surfaces of the
- 4 copper structures are exposed and substantially co-planar with a top surface of
- 5 the hydrophobic interlayer dielectric layer; and
- 6 selectively depositing a cobalt capping layer on the top surfaces of the
- 7 plurality of copper structures with substantially no deposition of the cobalt on the
- 8 top surface of the interlayer dielectric layer, using an aqueous electro-less bath
- 9 and applying sonic energy to the aqueous electro-less bath.
- 1 2. The method of claim 1, wherein the applying of sonic energy comprises
- 2 applying a selected one of mega and ultra sonic energy.
- 1 3. The method of claim 1, wherein the applying of sonic energy comprises
- 2 applying the sonic energy at a frequency range of 10 to 1200 kilohertz.
- 1 4. The method of claim 1, wherein the applying of sonic energy comprises
- 2 applying the sonic energy at a power level in a range of 1 to 5 watts/cm².
- 1 5. The method of claim 1, wherein the method further comprises
- 2 simultaneously rinsing and applying sonic energy to the hydrophobic interlayer
- 3 dielectric layer after said selective deposition of cobalt.
- 1 6. A method comprising

IPG No: P17263

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providing a wafer comprising a plurality of copper structures partially encased in a hydrophobic interlayer dielectric layer, where top surfaces of the copper structures are exposed and substantially co-planar with a top surface of the hydrophobic interlayer dielectric layer;

selectively depositing a cobalt capping layer on the top surfaces of the plurality of copper structures; and simultaneously rinsing and applying sonic energy to the hydrophobic interlayer dielectric layer to decrease the amount of cobalt particles adhered to the hydrophobic interlayer dielectric layer.

- 7. The method of claim 6, wherein the applying of sonic energy comprises applying a selected one of mega and ultra sonic energy.
- 1 8. The method of claim 6, wherein the applying of sonic energy comprises 2 applying the sonic energy at a frequency range of 10 to 1200 kilohertz.
- 1 9. The method of claim 6, wherein the applying of sonic energy comprises 2 applying the sonic energy at a power level in a range of 1 to 5 watts/cm².
 - 10. An apparatus comprising:
- 2 a chamber adapted for cobalt deposition, including a holder to hold a 3 substrate with a hydrophobic interlayer dielectric layer; and
- a sonic energy generator coupled to the chamber and adapted to allow

 sonic energy be applied during deposition of cobalt to cap a number of

 copper structures disposed on the hydrophobic interlayer dielectric

7 layer.

IPG No: P17263

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1 11. The apparatus of claim 10, wherein the apparatus further comprises at

- 2 least one tank coupled to the chamber and adapted to store and to provide the
- interlayer dielectric layer with an aqueous electro-less bath; and the sonic energy
- 4 generator is also adapted to allow sonic energy be applied during the provision of
- 5 the aqueous electro-less bath.
- 1 12. The apparatus of claim 10, wherein the sonic energy generator is adapted
- 2 to apply a selected one of mega and ultra sonic energy.
- 3 13. The apparatus of claim 10, wherein the sonic energy generator is adapted
- 4 to apply the sonic energy at a frequency range of 10 to 1200 kilohertz.
- 1 14. The apparatus of claim 10, wherein the sonic energy generator is adapted
- to apply the sonic energy at a power level in a range of 1 to 5 watts/cm².
- 1 15. An apparatus comprising:
- 2 a chamber including a holder to hold a substrate with a hydrophobic
- 3 interlayer dielectric layer;
- 4 at least one tank coupled to the chamber and adapted to store and to
- 5 provide the interlayer dielectric layer with an aqueous electro-less bath;
- 6 and
- 7 a sonic energy generator coupled to the chamber and adapted to allow
- 8 sonic energy be applied during the provision of the aqueous electro-
- 9 less bath.
- 1 16. The apparatus of claim 15, wherein the sonic energy generator is adapted
- 2 to apply a selected one of mega and ultra sonic energy.

IPG No: P17263

3 17. The apparatus of claim 15, wherein the sonic energy generator is adapted

- 4 to apply the sonic energy at a frequency range of 10 to 1200 kilohertz.
- 1 18. The apparatus of claim 15, wherein the sonic energy generator is adapted
- 2 to apply the sonic energy at a power level in a range of 1 to 5 watts/cm².
- 1 19. An apparatus comprising:
- a hydrophobic interlayer dielectric layer substantially free of adhered
- 3 cobalt particles;
- 4 a copper structure disposed on the interlayer dielectric layer; and
- 5 a cobalt capping layer disposed on a top surface of the copper structure.
- 1 20. The apparatus of claim 10, wherein the hydrophobic interlayer dielectric
- 2 layer has a low K value where K is a dielectric constant lower than 3.5.
- 1 21. A system comprising:
- 2 a semiconductor package comprising a die, the die having
- a hydrophobic interlayer dielectric layer that is substantially free of
- 4 adhered cobalt, and a plurality of cobalt capped copper structures
- 5 disposed on the interlayer dielectric layer;
- a bus coupled to the semiconductor package; and
- 7 a network interface module coupled to the bus.
- 1 22. The system of claim 21, wherein the semiconductor package comprises a
- 2 semiconductor device selected from a semiconductor device group consisting of
- a microprocessor, a memory device, a graphics processor, a digital signal
- 4 processor, and a crypto processor.

IPG No: P17263

1 23. The system of claim 22, wherein the system is a selected one of a a digital

2 versatile disk player, an audio/video media player, and a set-top box.